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Understanding **Embedded - FPGAs (Field Programmable Gate Array)**

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

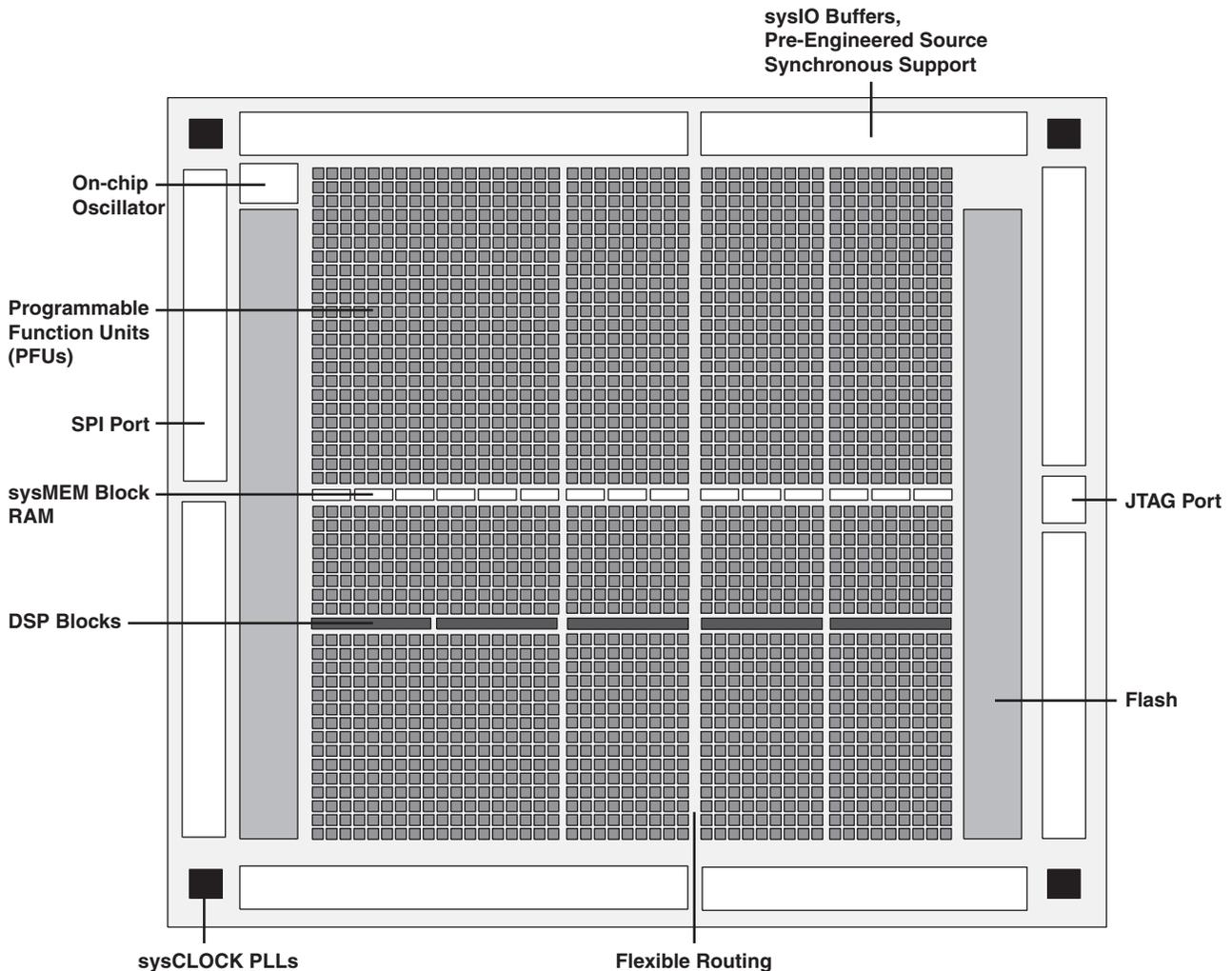
Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	3625
Number of Logic Elements/Cells	29000
Total RAM Bits	396288
Number of I/O	363
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	484-BBGA
Supplier Device Package	484-FPBGA (23x23)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lfxp2-30e-5fn484c

Figure 2-1. Simplified Block Diagram, LatticeXP2-17 Device (Top Level)

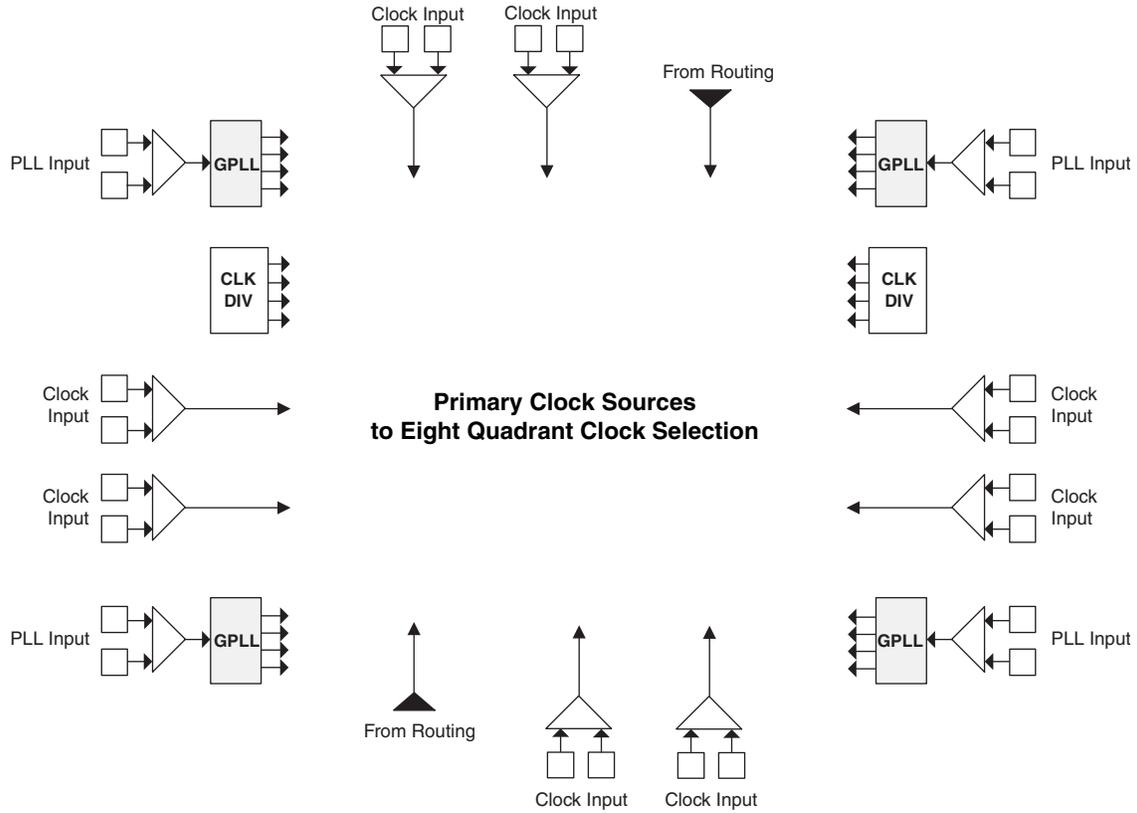


PFU Blocks

The core of the LatticeXP2 device is made up of logic blocks in two forms, PFUs and PFFs. PFUs can be programmed to perform logic, arithmetic, distributed RAM and distributed ROM functions. PFF blocks can be programmed to perform logic, arithmetic and ROM functions. Except where necessary, the remainder of this data sheet will use the term PFU to refer to both PFU and PFF blocks.

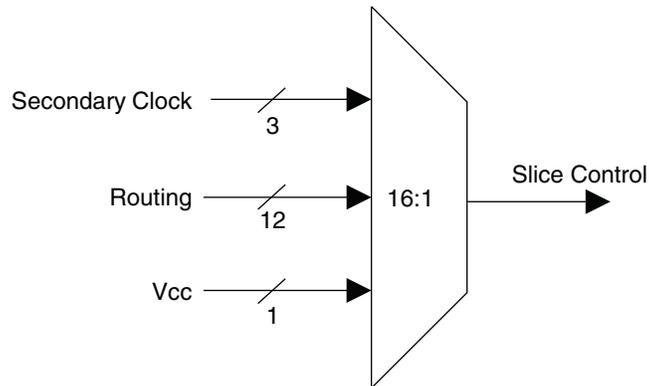
Each PFU block consists of four interconnected slices, numbered Slice 0 through Slice 3, as shown in Figure 2-2. All the interconnections to and from PFU blocks are from routing. There are 50 inputs and 23 outputs associated with each PFU block.

Figure 2-6. Primary Clock Sources for XP2-17



Note: This diagram shows sources for the XP2-17 device. Smaller LatticeXP2 devices have two GPLLs.

Figure 2-14. Slice0 through Slice2 Control Selection



Edge Clock Routing

LatticeXP2 devices have eight high-speed edge clocks that are intended for use with the PIOs in the implementation of high-speed interfaces. Each device has two edge clocks per edge. Figure 2-15 shows the selection muxes for these clocks.

Figure 2-15. Edge Clock Mux Connections

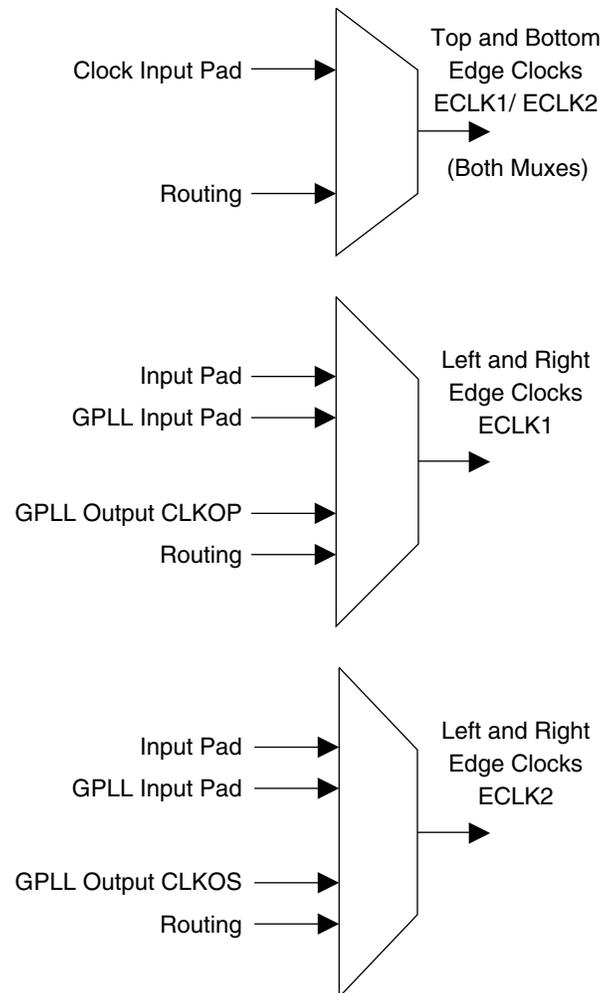
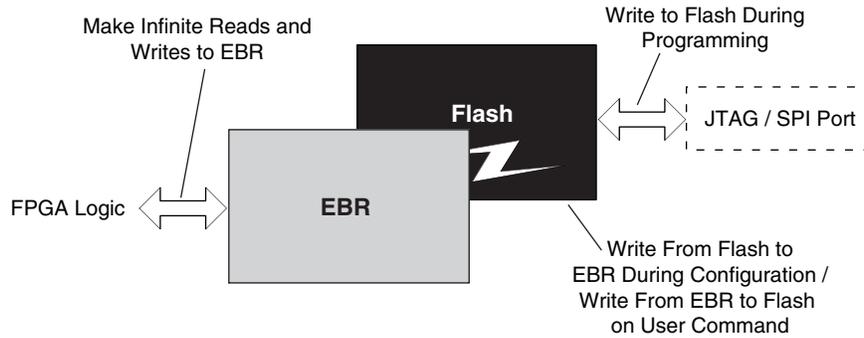


Figure 2-16. FlashBAK Technology



Memory Cascading

Larger and deeper blocks of RAMs can be created using EBR sysMEM Blocks. Typically, the Lattice design tools cascade memory transparently, based on specific design inputs.

Single, Dual and Pseudo-Dual Port Modes

In all the sysMEM RAM modes the input data and address for the ports are registered at the input of the memory array. The output data of the memory is optionally registered at the output.

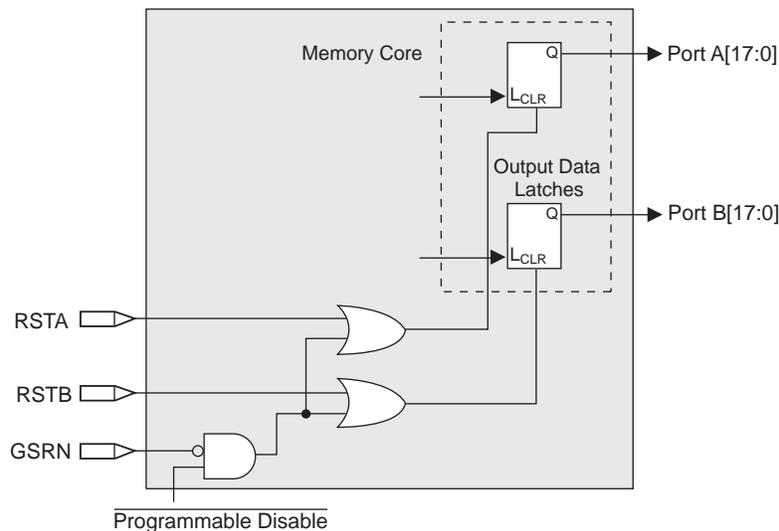
EBR memory supports two forms of write behavior for single port or dual port operation:

1. Normal – Data on the output appears only during a read cycle. During a write cycle, the data (at the current address) does not appear on the output. This mode is supported for all data widths.
2. Write Through – A copy of the input data appears at the output of the same port during a write cycle. This mode is supported for all data widths.

Memory Core Reset

The memory array in the EBR utilizes latches at the A and B output ports. These latches can be reset asynchronously or synchronously. RSTA and RSTB are local signals, which reset the output latches associated with Port A and Port B respectively. GSRN, the global reset signal, resets both ports. The output data latches and associated resets for both ports are as shown in Figure 2-17.

Figure 2-17. Memory Core Reset

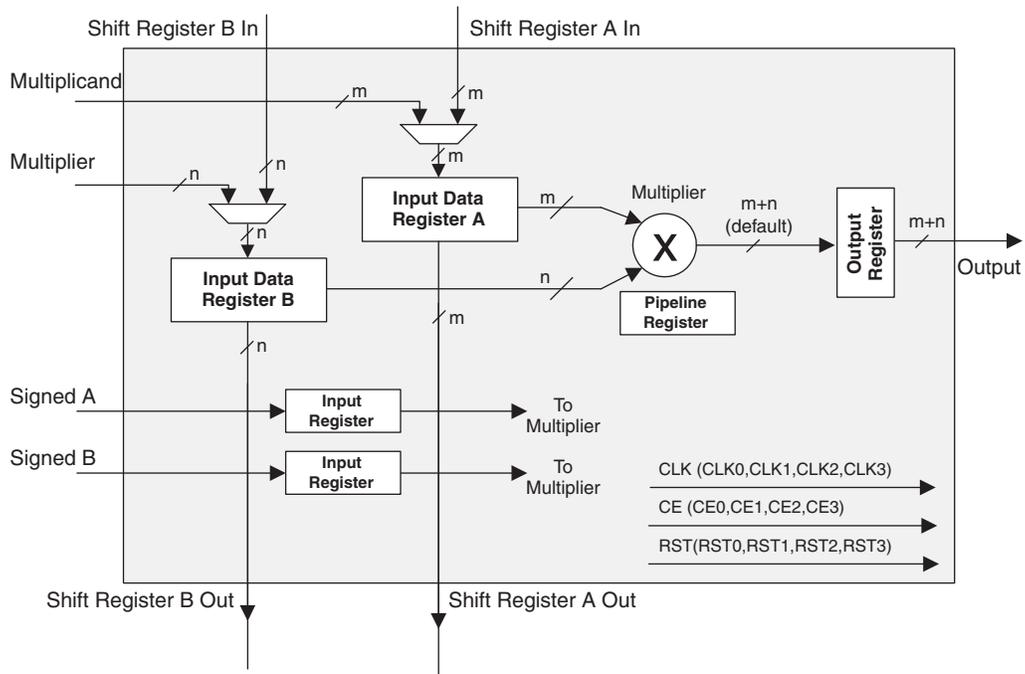


- In the 'Signed/Unsigned' options the operands can be switched between signed and unsigned on every cycle.
- In the 'Add/Sub' option the Accumulator can be switched between addition and subtraction on every cycle.
- The loading of operands can switch between parallel and serial operations.

MULT sysDSP Element

This multiplier element implements a multiply with no addition or accumulator nodes. The two operands, A and B, are multiplied and the result is available at the output. The user can enable the input/output and pipeline registers. Figure 2-20 shows the MULT sysDSP element.

Figure 2-20. MULT sysDSP Element



register. Similarly, CE and RST are selected from their four respective sources (CE0, CE1, CE2, CE3 and RST0, RST1, RST2, RST3) at each input register, pipeline register and output register.

Signed and Unsigned with Different Widths

The DSP block supports other widths, in addition to x9, x18 and x36 widths, of signed and unsigned multipliers. For unsigned operands, unused upper data bits should be filled to create a valid x9, x18 or x36 operand. For signed two's complement operands, sign extension of the most significant bit should be performed until x9, x18 or x36 width is reached. Table 2-7 provides an example of this.

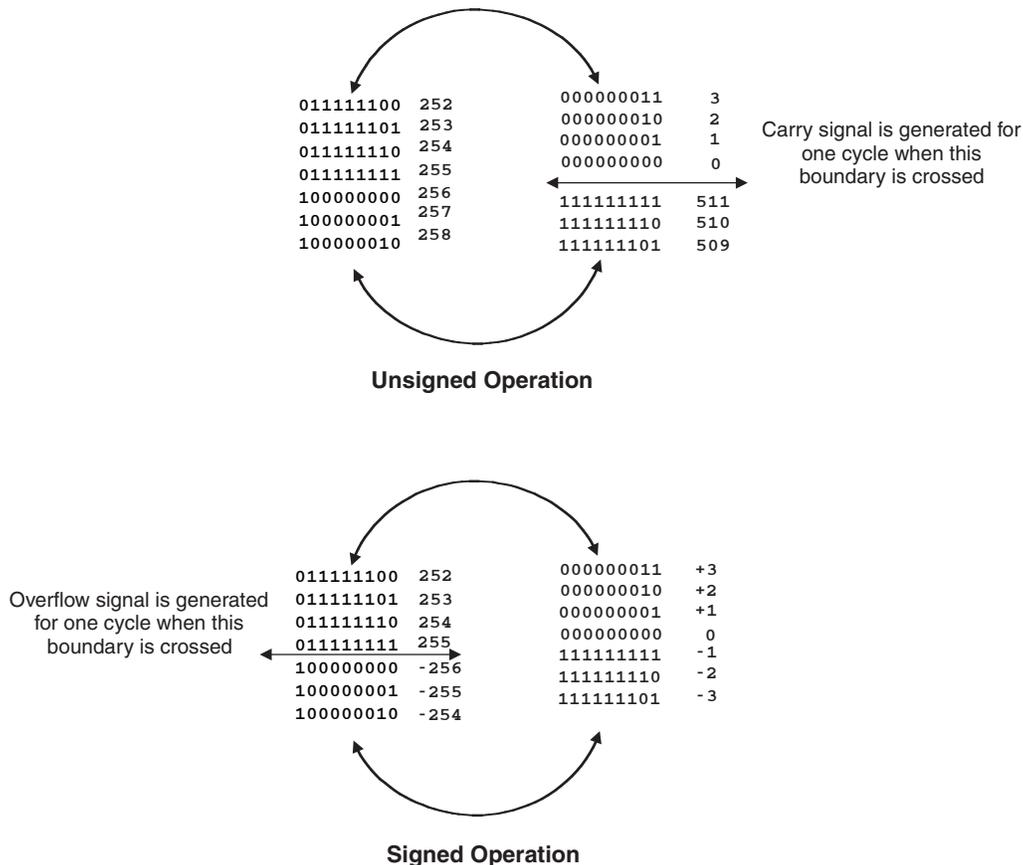
Table 2-7. Sign Extension Example

Number	Unsigned	Unsigned 9-bit	Unsigned 18-bit	Signed	Two's Complement Signed 9 Bits	Two's Complement Signed 18 Bits
+5	0101	000000101	0000000000000000101	0101	000000101	0000000000000000101
-6	N/A	N/A	N/A	1010	11111010	111111111111111010

OVERFLOW Flag from MAC

The sysDSP block provides an overflow output to indicate that the accumulator has overflowed. "Roll-over" occurs and an overflow signal is indicated when any of the following is true: two unsigned numbers are added and the result is a smaller number than the accumulator, two positive numbers are added with a negative sum or two negative numbers are added with a positive sum. Note that when overflow occurs the overflow flag is present for only one cycle. By counting these overflow pulses in FPGA logic, larger accumulators can be constructed. The conditions for the overflow signal for signed and unsigned operands are listed in Figure 2-24.

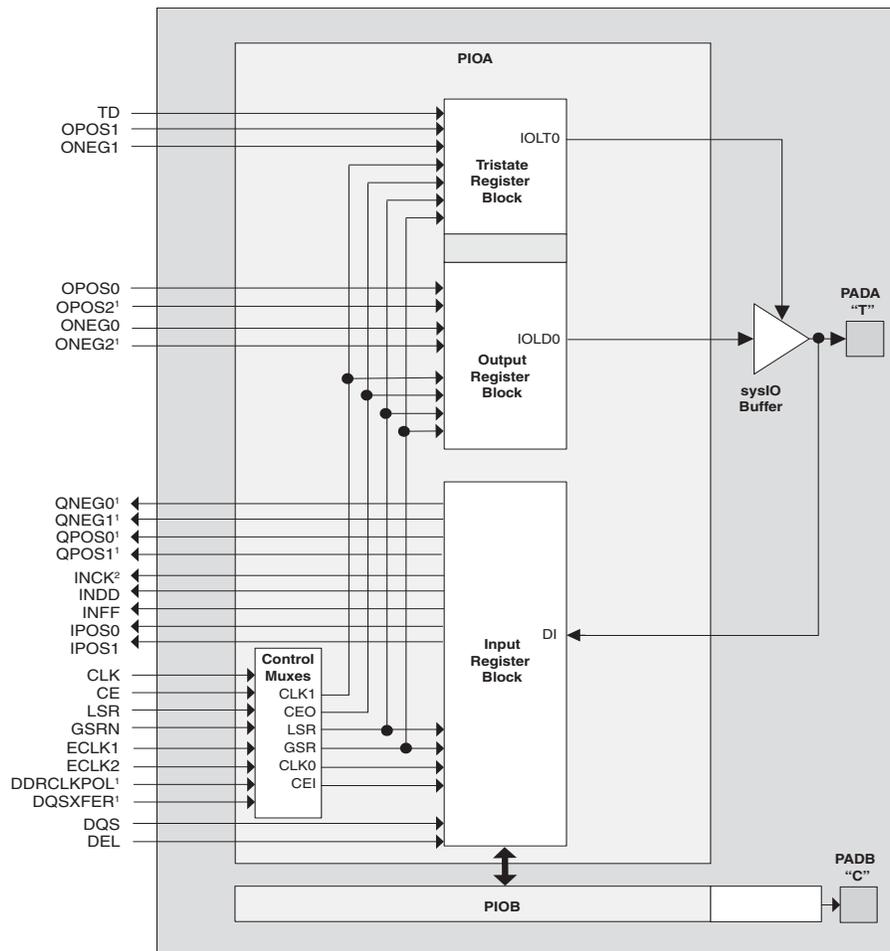
Figure 2-24. Accumulator Overflow/Underflow



Programmable I/O Cells (PIC)

Each PIC contains two PIOs connected to their respective sysIO buffers as shown in Figure 2-25. The PIO Block supplies the output data (DO) and the tri-state control signal (TO) to the sysIO buffer and receives input from the buffer. Table 2-11 provides the PIO signal list.

Figure 2-25. PIC Diagram



1. Signals are available on left/right/bottom edges only.
2. Selected blocks.

Two adjacent PIOs can be joined to provide a differential I/O pair (labeled as "T" and "C") as shown in Figure 2-25. The PAD Labels "T" and "C" distinguish the two PIOs. Approximately 50% of the PIO pairs on the left and right edges of the device can be configured as true LVDS outputs. All I/O pairs can operate as inputs.

Table 2-11. PIO Signal List

Name	Type	Description
CE	Control from the core	Clock enables for input and output block flip-flops
CLK	Control from the core	System clocks for input and output blocks
ECLK1, ECLK2	Control from the core	Fast edge clocks
LSR	Control from the core	Local Set/Reset
GSRN	Control from routing	Global Set/Reset (active low)
INCK ²	Input to the core	Input to Primary Clock Network or PLL reference inputs
DQS	Input to PIO	DQS signal from logic (routing) to PIO
INDD	Input to the core	Unregistered data input to core
INFF	Input to the core	Registered input on positive edge of the clock (CLK0)
IPOS0, IPOS1	Input to the core	Double data rate registered inputs to the core
QPOS0 ¹ , QPOS1 ¹	Input to the core	Gearbox pipelined inputs to the core
QNEG0 ¹ , QNEG1 ¹	Input to the core	Gearbox pipelined inputs to the core
OPOS0, ONEG0, OPOS2, ONEG2	Output data from the core	Output signals from the core for SDR and DDR operation
OPOS1 ONEG1	Tristate control from the core	Signals to Tristate Register block for DDR operation
DEL[3:0]	Control from the core	Dynamic input delay control bits
TD	Tristate control from the core	Tristate signal from the core used in SDR operation
DDRCLKPOL	Control from clock polarity bus	Controls the polarity of the clock (CLK0) that feed the DDR input block
DQSXFER	Control from core	Controls signal to the Output block

1. Signals available on left/right/bottom only.

2. Selected I/O.

PIO

The PIO contains four blocks: an input register block, output register block, tristate register block and a control logic block. These blocks contain registers for operating in a variety of modes along with necessary clock and selection logic.

Input Register Block

The input register blocks for PIOs contain delay elements and registers that can be used to condition high-speed interface signals, such as DDR memory interfaces and source synchronous interfaces, before they are passed to the device core. Figure 2-26 shows the diagram of the input register block.

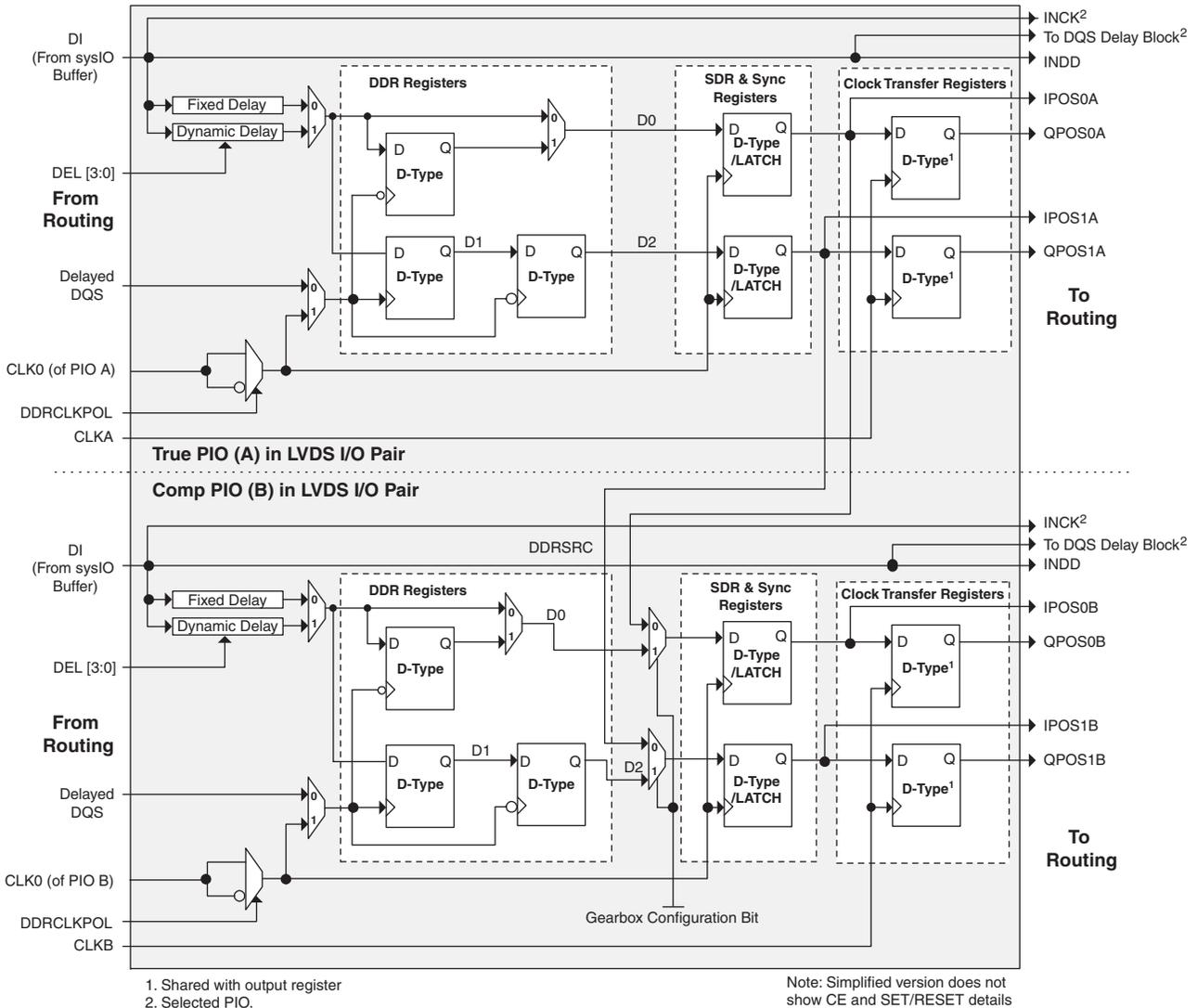
Input signals are fed from the sysIO buffer to the input register block (as signal DI). If desired, the input signal can bypass the register and delay elements and be used directly as a combinatorial signal (INDD), a clock (INCK) and, in selected blocks, the input to the DQS delay block. If an input delay is desired, designers can select either a fixed delay or a dynamic delay DEL[3:0]. The delay, if selected, reduces input register hold time requirements when using a global clock.

The input block allows three modes of operation. In the Single Data Rate (SDR) mode, the data is registered, by one of the registers in the SDR Sync register block, with the system clock. In DDR mode two registers are used to sample the data on the positive and negative edges of the DQS signal which creates two data streams, D0 and D2. D0 and D2 are synchronized with the system clock before entering the core. Further information on this topic can be found in the DDR Memory Support section of this data sheet.

By combining input blocks of the complementary PIOs and sharing registers from output blocks, a gearbox function can be implemented, that takes a double data rate signal applied to PIOA and converts it as four data streams, IPOS0A, IPOS1A, IPOS0B and IPOS1B. Figure 2-26 shows the diagram using this gearbox function. For more information on this topic, please see TN1138, [LatticeXP2 High Speed I/O Interface](#).

The signal DDRCLKPOL controls the polarity of the clock used in the synchronization registers. It ensures adequate timing when data is transferred from the DQS to system clock domain. For further discussion on this topic, see the DDR Memory section of this data sheet.

Figure 2-26. Input Register Block



Output Register Block

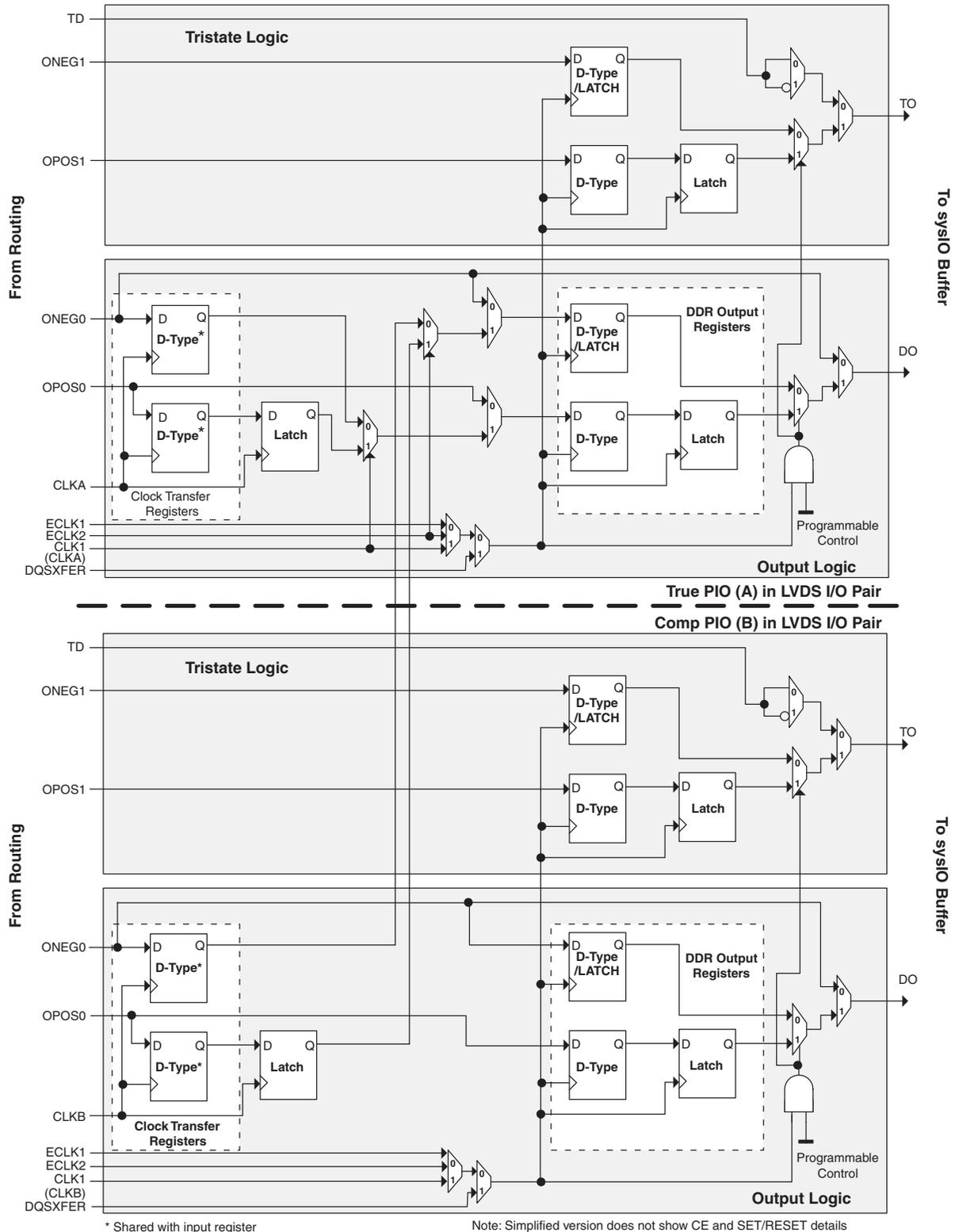
The output register block provides the ability to register signals from the core of the device before they are passed to the sysIO buffers. The blocks on the PIOs on the left, right and bottom contain registers for SDR operation that are combined with an additional latch for DDR operation. Figure 2-27 shows the diagram of the Output Register Block for PIOs.

In SDR mode, ONEG0 feeds one of the flip-flops that then feeds the output. The flip-flop can be configured as a D-type or latch. In DDR mode, ONEG0 and OPOS0 are fed into registers on the positive edge of the clock. At the next clock cycle the registered OPOS0 is latched. A multiplexer running off the same clock cycle selects the correct register to feed the output (D0).

By combining output blocks of the complementary PIOs and sharing some registers from input blocks, a gearbox function can be implemented, to take four data streams ONEG0A, ONEG1A, ONEG1B and ONEG1B. Figure 2-27

shows the diagram using this gearbox function. For more information on this topic, see TN1138, [LatticeXP2 High Speed I/O Interface](#).

Figure 2-27. Output and Tristate Block



DQSXFER

LatticeXP2 devices provide a DQSXFER signal to the output buffer to assist it in data transfer to DDR memories that require DQS strobe be shifted 90°. This shifted DQS strobe is generated by the DQSDEL block. The DQSXFER signal runs the span of the data bus.

sysIO Buffer

Each I/O is associated with a flexible buffer referred to as a sysIO buffer. These buffers are arranged around the periphery of the device in groups referred to as banks. The sysIO buffers allow users to implement the wide variety of standards that are found in today's systems including LVCMOS, SSTL, HSTL, LVDS and LVPECL.

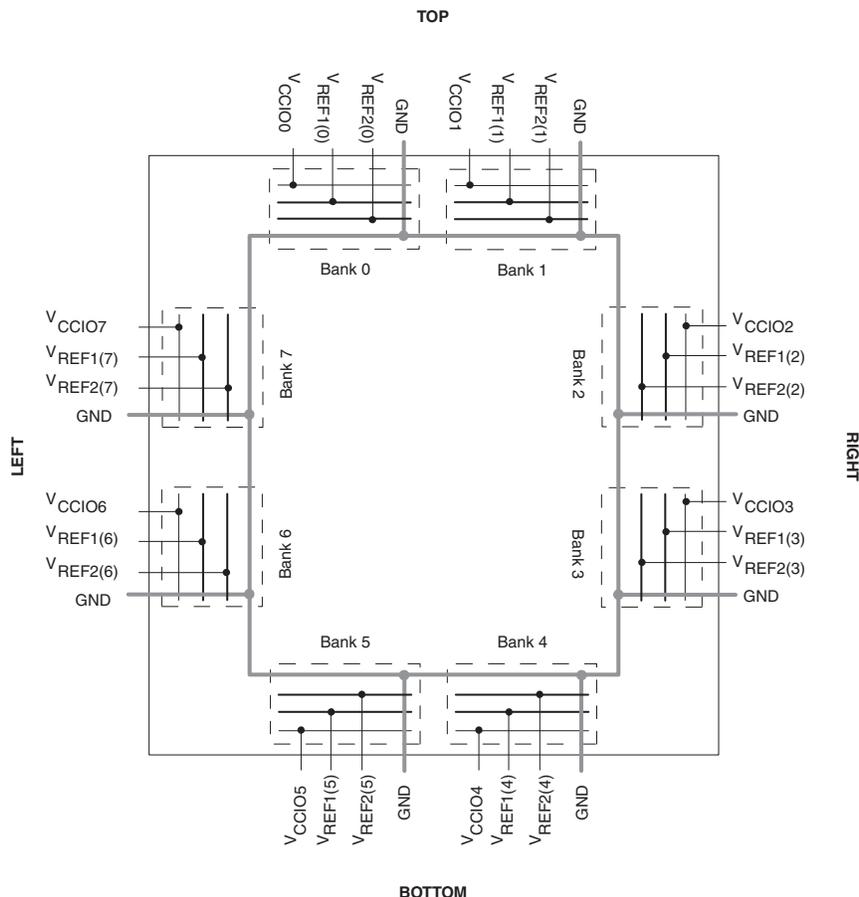
sysIO Buffer Banks

LatticeXP2 devices have eight sysIO buffer banks for user I/Os arranged two per side. Each bank is capable of supporting multiple I/O standards. Each sysIO bank has its own I/O supply voltage (V_{CCIO}). In addition, each bank has voltage references, V_{REF1} and V_{REF2} , that allow it to be completely independent from the others. Figure 2-32 shows the eight banks and their associated supplies.

In LatticeXP2 devices, single-ended output buffers and ratioed input buffers (LVTTTL, LVCMOS and PCI) are powered using V_{CCIO} . LVTTTL, LVCMOS33, LVCMOS25 and LVCMOS12 can also be set as fixed threshold inputs independent of V_{CCIO} .

Each bank can support up to two separate V_{REF} voltages, V_{REF1} and V_{REF2} , that set the threshold for the referenced input buffers. Some dedicated I/O pins in a bank can be configured to be a reference voltage supply pin. Each I/O is individually configurable based on the bank's supply and reference voltages.

Figure 2-32. LatticeXP2 Banks



LatticeXP2 devices contain two types of sysIO buffer pairs.

1. Top and Bottom (Banks 0, 1, 4 and 5) sysIO Buffer Pairs (Single-Ended Outputs Only)

The sysIO buffer pairs in the top banks of the device consist of two single-ended output drivers and two sets of single-ended input buffers (both ratioed and referenced). One of the referenced input buffers can also be configured as a differential input.

The two pads in the pair are described as “true” and “comp”, where the true pad is associated with the positive side of the differential input buffer and the comp (complementary) pad is associated with the negative side of the differential input buffer.

Only the I/Os on the top and bottom banks have programmable PCI clamps.

2. Left and Right (Banks 2, 3, 6 and 7) sysIO Buffer Pairs (50% Differential and 100% Single-Ended Outputs)

The sysIO buffer pairs in the left and right banks of the device consist of two single-ended output drivers, two sets of single-ended input buffers (both ratioed and referenced) and one differential output driver. One of the referenced input buffers can also be configured as a differential input.

The two pads in the pair are described as “true” and “comp”, where the true pad is associated with the positive side of the differential I/O, and the comp pad is associated with the negative side of the differential I/O.

LVDS differential output drivers are available on 50% of the buffer pairs on the left and right banks.

Typical sysIO I/O Behavior During Power-up

The internal power-on-reset (POR) signal is deactivated when V_{CC} , $V_{CCCONFIG}$ (V_{CCIO7}) and V_{CCAUX} have reached satisfactory levels. After the POR signal is deactivated, the FPGA core logic becomes active. It is the user's responsibility to ensure that all other V_{CCIO} banks are active with valid input logic levels to properly control the output logic states of all the I/O banks that are critical to the application. During power up and before the FPGA core logic becomes active, all user I/Os will be high-impedance with weak pull-up. Please refer to TN1136, [LatticeXP2 sysIO Usage Guide](#) for additional information.

The V_{CC} and V_{CCAUX} supply the power to the FPGA core fabric, whereas the V_{CCIO} supplies power to the I/O buffers. In order to simplify system design while providing consistent and predictable I/O behavior, it is recommended that the I/O buffers be powered-up prior to the FPGA core fabric. V_{CCIO} supplies should be powered-up before or together with the V_{CC} and V_{CCAUX} supplies.

Supported sysIO Standards

The LatticeXP2 sysIO buffer supports both single-ended and differential standards. Single-ended standards can be further subdivided into LVCMOS, LVTTTL and other standards. The buffers support the LVTTTL, LVCMOS 1.2V, 1.5V, 1.8V, 2.5V and 3.3V standards. In the LVCMOS and LVTTTL modes, the buffer has individual configuration options for drive strength, bus maintenance (weak pull-up, weak pull-down, or a bus-keeper latch) and open drain. Other single-ended standards supported include SSTL and HSTL. Differential standards supported include LVDS, MLVDS, BLVDS, LVPECL, RSDS, differential SSTL and differential HSTL. Tables 2-12 and 2-13 show the I/O standards (together with their supply and reference voltages) supported by LatticeXP2 devices. For further information on utilizing the sysIO buffer to support a variety of standards please see TN1136, [LatticeXP2 sysIO Usage Guide](#).

Table 2-13. Supported Output Standards

Output Standard	Drive	V _{CCIO} (Nom.)
Single-ended Interfaces		
LVTTTL	4mA, 8mA, 12mA, 16mA, 20mA	3.3
LVC MOS33	4mA, 8mA, 12mA 16mA, 20mA	3.3
LVC MOS25	4mA, 8mA, 12mA, 16mA, 20mA	2.5
LVC MOS18	4mA, 8mA, 12mA, 16mA	1.8
LVC MOS15	4mA, 8mA	1.5
LVC MOS12	2mA, 6mA	1.2
LVC MOS33, Open Drain	4mA, 8mA, 12mA 16mA, 20mA	—
LVC MOS25, Open Drain	4mA, 8mA, 12mA 16mA, 20mA	—
LVC MOS18, Open Drain	4mA, 8mA, 12mA 16mA	—
LVC MOS15, Open Drain	4mA, 8mA	—
LVC MOS12, Open Drain	2mA, 6mA	—
PCI33	N/A	3.3
HSTL18 Class I, II	N/A	1.8
HSTL15 Class I	N/A	1.5
SSTL33 Class I, II	N/A	3.3
SSTL25 Class I, II	N/A	2.5
SSTL18 Class I, II	N/A	1.8
Differential Interfaces		
Differential SSTL33, Class I, II	N/A	3.3
Differential SSTL25, Class I, II	N/A	2.5
Differential SSTL18, Class I, II	N/A	1.8
Differential HSTL18, Class I, II	N/A	1.8
Differential HSTL15, Class I	N/A	1.5
LVDS ^{1,2}	N/A	2.5
MLVDS ¹	N/A	2.5
BLVDS ¹	N/A	2.5
LVPECL ¹	N/A	3.3
RSDS ¹	N/A	2.5
LVC MOS33D ¹	4mA, 8mA, 12mA, 16mA, 20mA	3.3

1. Emulated with external resistors.

2. On the left and right edges, LVDS outputs are supported with a dedicated differential output driver on 50% of the I/Os. This solution does not require external resistors at the driver.

Hot Socketing

LatticeXP2 devices have been carefully designed to ensure predictable behavior during power-up and power-down. Power supplies can be sequenced in any order. During power-up and power-down sequences, the I/Os remain in tri-state until the power supply voltage is high enough to ensure reliable operation. In addition, leakage into I/O pins is controlled to within specified limits. This allows for easy integration with the rest of the system. These capabilities make the LatticeXP2 ideal for many multiple power supply and hot-swap applications.

IEEE 1149.1-Compliant Boundary Scan Testability

All LatticeXP2 devices have boundary scan cells that are accessed through an IEEE 1149.1 compliant Test Access Port (TAP). This allows functional testing of the circuit board, on which the device is mounted, through a serial scan path that can access all critical logic nodes. Internal registers are linked internally, allowing test data to be shifted in

Absolute Maximum Ratings^{1, 2, 3}

Supply Voltage V_{CC}	-0.5 to 1.32V
Supply Voltage V_{CCAUX}	-0.5 to 3.75V
Supply Voltage V_{CCJ}	-0.5 to 3.75V
Supply Voltage V_{CCPLL} ⁴	-0.5 to 3.75V
Output Supply Voltage V_{CCIO}	-0.5 to 3.75V
Input or I/O Tristate Voltage Applied ⁵	-0.5 to 3.75V
Storage Temperature (Ambient)	-65 to 150°C
Junction Temperature Under Bias (T_j)	+125°C

1. Stress above those listed under the “Absolute Maximum Ratings” may cause permanent damage to the device. Functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.
2. Compliance with the Lattice [Thermal Management](#) document is required.
3. All voltages referenced to GND.
4. V_{CCPLL} only available on csBGA, PQFP and TQFP packages.
5. Overshoot and undershoot of -2V to ($V_{IHMAX} + 2$) volts is permitted for a duration of <20 ns.

Recommended Operating Conditions

Symbol	Parameter	Min.	Max.	Units
V_{CC}	Core Supply Voltage	1.14	1.26	V
V_{CCAUX} ^{4, 5}	Auxiliary Supply Voltage	3.135	3.465	V
V_{CCPLL} ¹	PLL Supply Voltage	3.135	3.465	V
V_{CCIO} ^{2, 3, 4}	I/O Driver Supply Voltage	1.14	3.465	V
V_{CCJ} ²	Supply Voltage for IEEE 1149.1 Test Access Port	1.14	3.465	V
t_{JCOM}	Junction Temperature, Commercial Operation	0	85	°C
t_{JIND}	Junction Temperature, Industrial Operation	-40	100	°C

1. V_{CCPLL} only available on csBGA, PQFP and TQFP packages.
2. If V_{CCIO} or V_{CCJ} is set to 1.2 V, they must be connected to the same power supply as V_{CC} . If V_{CCIO} or V_{CCJ} is set to 3.3V, they must be connected to the same power supply as V_{CCAUX} .
3. See recommended voltages by I/O standard in subsequent table.
4. To ensure proper I/O behavior, V_{CCIO} must be turned off at the same time or earlier than V_{CCAUX} .
5. In fpBGA and ftBGA packages, the PLLs are connected to, and powered from, the auxiliary power supply.

On-Chip Flash Memory Specifications

Symbol	Parameter	Max.	Units
N_{PROG}	Flash Programming Cycles per $t_{RETENTION}$ ¹	10,000	Cycles
	Flash Functional Programming Cycles	100,000	

1. The minimum data retention, $t_{RETENTION}$, is 20 years.

Hot Socketing Specifications^{1, 2, 3, 4}

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
I_{DK}	Input or I/O Leakage Current	$0 \leq V_{IN} \leq V_{IH} (MAX.)$	—	—	+/-1	mA

1. Insensitive to sequence of V_{CC} , V_{CCAUX} and V_{CCIO} . However, assumes monotonic rise/fall rates for V_{CC} , V_{CCAUX} and V_{CCIO} .
2. $0 \leq V_{CC} \leq V_{CC} (MAX)$, $0 \leq V_{CCIO} \leq V_{CCIO} (MAX)$ or $0 \leq V_{CCAUX} \leq V_{CCAUX} (MAX)$.
3. I_{DK} is additive to I_{PU} , I_{PW} or I_{BH} .
4. LVCMOS and LVTTL only.

ESD Performance

Please refer to the [LatticeXP2 Product Family Qualification Summary](#) for complete qualification data, including ESD performance.

DC Electrical Characteristics

Over Recommended Operating Conditions

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
I_{IL} , I_{IH}^1	Input or I/O Low Leakage	$0 \leq V_{IN} \leq V_{CCIO}$	—	—	10	μA
		$V_{CCIO} \leq V_{IN} \leq V_{IH} (MAX)$	—	—	150	μA
I_{PU}	I/O Active Pull-up Current	$0 \leq V_{IN} \leq 0.7 V_{CCIO}$	-30	—	-150	μA
I_{PD}	I/O Active Pull-down Current	$V_{IL} (MAX) \leq V_{IN} \leq V_{CCIO}$	30	—	210	μA
I_{BHLS}	Bus Hold Low Sustaining Current	$V_{IN} = V_{IL} (MAX)$	30	—	—	μA
I_{BHHS}	Bus Hold High Sustaining Current	$V_{IN} = 0.7 V_{CCIO}$	-30	—	—	μA
I_{BHLO}	Bus Hold Low Overdrive Current	$0 \leq V_{IN} \leq V_{CCIO}$	—	—	210	μA
I_{BHHO}	Bus Hold High Overdrive Current	$0 \leq V_{IN} \leq V_{CCIO}$	—	—	-150	μA
V_{BHT}	Bus Hold Trip Points		$V_{IL} (MAX)$	—	$V_{IH} (MIN)$	V
C1	I/O Capacitance ²	$V_{CCIO} = 3.3V, 2.5V, 1.8V, 1.5V, 1.2V$, $V_{CC} = 1.2V, V_{IO} = 0$ to $V_{IH} (MAX)$	—	8	—	pf
C2	Dedicated Input Capacitance	$V_{CCIO} = 3.3V, 2.5V, 1.8V, 1.5V, 1.2V$, $V_{CC} = 1.2V, V_{IO} = 0$ to $V_{IH} (MAX)$	—	6	—	pf

1. Input or I/O leakage current is measured with the pin configured as an input or as an I/O with the output driver tri-stated. It is not measured with the output driver active. Bus maintenance circuits are disabled.
2. T_A 25°C, $f = 1.0$ MHz.

LatticeXP2 External Switching Characteristics (Continued)

Over Recommended Operating Conditions

Parameter	Description	Device	-7		-6		-5		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
t_{HE}	Clock to Data Hold - PIO Input Register	XP2-5	1.00	—	1.30	—	1.60	—	ns
		XP2-8	1.00	—	1.30	—	1.60	—	ns
		XP2-17	1.00	—	1.30	—	1.60	—	ns
		XP2-30	1.20	—	1.60	—	1.90	—	ns
		XP2-40	1.20	—	1.60	—	1.90	—	ns
t_{SU_DELE}	Clock to Data Setup - PIO Input Register with Data Input Delay	XP2-5	1.00	—	1.30	—	1.60	—	ns
		XP2-8	1.00	—	1.30	—	1.60	—	ns
		XP2-17	1.00	—	1.30	—	1.60	—	ns
		XP2-30	1.20	—	1.60	—	1.90	—	ns
		XP2-40	1.20	—	1.60	—	1.90	—	ns
t_{H_DELE}	Clock to Data Hold - PIO Input Register with Input Data Delay	XP2-5	0.00	—	0.00	—	0.00	—	ns
		XP2-8	0.00	—	0.00	—	0.00	—	ns
		XP2-17	0.00	—	0.00	—	0.00	—	ns
		XP2-30	0.00	—	0.00	—	0.00	—	ns
		XP2-40	0.00	—	0.00	—	0.00	—	ns
f_{MAX_IOE}	Clock Frequency of I/O and PFU Register	XP2	—	420	—	357	—	311	MHz
General I/O Pin Parameters (using Primary Clock with PLL)¹									
t_{COPLL}	Clock to Output - PIO Output Register	XP2-5	—	3.00	—	3.30	—	3.70	ns
		XP2-8	—	3.00	—	3.30	—	3.70	ns
		XP2-17	—	3.00	—	3.30	—	3.70	ns
		XP2-30	—	3.00	—	3.30	—	3.70	ns
		XP2-40	—	3.00	—	3.30	—	3.70	ns
t_{SUPLL}	Clock to Data Setup - PIO Input Register	XP2-5	1.00	—	1.20	—	1.40	—	ns
		XP2-8	1.00	—	1.20	—	1.40	—	ns
		XP2-17	1.00	—	1.20	—	1.40	—	ns
		XP2-30	1.00	—	1.20	—	1.40	—	ns
		XP2-40	1.00	—	1.20	—	1.40	—	ns
t_{HPLL}	Clock to Data Hold - PIO Input Register	XP2-5	0.90	—	1.10	—	1.30	—	ns
		XP2-8	0.90	—	1.10	—	1.30	—	ns
		XP2-17	0.90	—	1.10	—	1.30	—	ns
		XP2-30	1.00	—	1.20	—	1.40	—	ns
		XP2-40	1.00	—	1.20	—	1.40	—	ns
t_{SU_DELPLL}	Clock to Data Setup - PIO Input Register with Data Input Delay	XP2-5	1.90	—	2.10	—	2.30	—	ns
		XP2-8	1.90	—	2.10	—	2.30	—	ns
		XP2-17	1.90	—	2.10	—	2.30	—	ns
		XP2-30	2.00	—	2.20	—	2.40	—	ns
		XP2-40	2.00	—	2.20	—	2.40	—	ns

LatticeXP2 Family Timing Adders^{1, 2, 3, 4}
Over Recommended Operating Conditions

Buffer Type	Description	-7	-6	-5	Units
Input Adjusters					
LVDS25	LVDS	-0.26	-0.11	0.04	ns
BLVDS25	BLVDS	-0.26	-0.11	0.04	ns
MLVDS	LVDS	-0.26	-0.11	0.04	ns
RSDS	RSDS	-0.26	-0.11	0.04	ns
LVPECL33	LVPECL	-0.26	-0.11	0.04	ns
HSTL18_I	HSTL_18 class I	-0.23	-0.08	0.07	ns
HSTL18_II	HSTL_18 class II	-0.23	-0.08	0.07	ns
HSTL18D_I	Differential HSTL 18 class I	-0.28	-0.13	0.02	ns
HSTL18D_II	Differential HSTL 18 class II	-0.28	-0.13	0.02	ns
HSTL15_I	HSTL_15 class I	-0.23	-0.09	0.06	ns
HSTL15D_I	Differential HSTL 15 class I	-0.28	-0.13	0.01	ns
SSTL33_I	SSTL_3 class I	-0.20	-0.04	0.12	ns
SSTL33_II	SSTL_3 class II	-0.20	-0.04	0.12	ns
SSTL33D_I	Differential SSTL_3 class I	-0.27	-0.11	0.04	ns
SSTL33D_II	Differential SSTL_3 class II	-0.27	-0.11	0.04	ns
SSTL25_I	SSTL_2 class I	-0.21	-0.06	0.10	ns
SSTL25_II	SSTL_2 class II	-0.21	-0.06	0.10	ns
SSTL25D_I	Differential SSTL_2 class I	-0.27	-0.12	0.03	ns
SSTL25D_II	Differential SSTL_2 class II	-0.27	-0.12	0.03	ns
SSTL18_I	SSTL_18 class I	-0.23	-0.08	0.07	ns
SSTL18_II	SSTL_18 class II	-0.23	-0.08	0.07	ns
SSTL18D_I	Differential SSTL_18 class I	-0.28	-0.13	0.02	ns
SSTL18D_II	Differential SSTL_18 class II	-0.28	-0.13	0.02	ns
LVTTTL33	LVTTTL	-0.09	0.05	0.18	ns
LVC MOS33	LVC MOS 3.3	-0.09	0.05	0.18	ns
LVC MOS25	LVC MOS 2.5	0.00	0.00	0.00	ns
LVC MOS18	LVC MOS 1.8	-0.23	-0.07	0.09	ns
LVC MOS15	LVC MOS 1.5	-0.20	-0.02	0.16	ns
LVC MOS12	LVC MOS 1.2	-0.35	-0.20	-0.04	ns
PCI33	3.3V PCI	-0.09	0.05	0.18	ns
Output Adjusters					
LVDS25E	LVDS 2.5 E ⁵	-0.25	0.02	0.30	ns
LVDS25	LVDS 2.5	-0.25	0.02	0.30	ns
BLVDS25	BLVDS 2.5	-0.28	0.00	0.28	ns
MLVDS	MLVDS 2.5 ⁵	-0.28	0.00	0.28	ns
RSDS	RSDS 2.5 ⁵	-0.25	0.02	0.30	ns
LVPECL33	LVPECL 3.3 ⁵	-0.37	-0.10	0.18	ns
HSTL18_I	HSTL_18 class I 8mA drive	-0.17	0.13	0.43	ns
HSTL18_II	HSTL_18 class II	-0.29	0.00	0.29	ns
HSTL18D_I	Differential HSTL 18 class I 8mA drive	-0.17	0.13	0.43	ns
HSTL18D_II	Differential HSTL 18 class II	-0.29	0.00	0.29	ns

sysCLOCK PLL Timing

Over Recommended Operating Conditions

Parameter	Description	Conditions	Min.	Typ.	Max.	Units
f _{IN}	Input Clock Frequency (CLKI, CLKFB)		10	—	435	MHz
f _{OUT}	Output Clock Frequency (CLKOP, CLKOS)		10	—	435	MHz
f _{OUT2}	K-Divider Output Frequency	CLKOK	0.078	—	217.5	MHz
		CLKOK2	3.3	—	145	MHz
f _{VCO}	PLL VCO Frequency		435	—	870	MHz
f _{PDF}	Phase Detector Input Frequency		10	—	435	MHz
AC Characteristics						
t _{DT}	Output Clock Duty Cycle	Default duty cycle selected ³	45	50	55	%
t _{CPA}	Coarse Phase Adjust		-5	0	5	%
t _{PH} ⁴	Output Phase Accuracy		-5	0	5	%
t _{OPJIT} ¹	Output Clock Period Jitter	f _{OUT} > 400 MHz	—	—	±50	ps
		100 MHz < f _{OUT} < 400 MHz	—	—	±125	ps
		f _{OUT} < 100 MHz	—	—	0.025	UIPP
t _{SK}	Input Clock to Output Clock Skew	N/M = integer	—	—	±240	ps
t _{OPW}	Output Clock Pulse Width	At 90% or 10%	1	—	—	ns
t _{LOCK} ²	PLL Lock-in Time	25 to 435 MHz	—	—	50	μs
		10 to 25 MHz	—	—	100	μs
t _{IPJIT}	Input Clock Period Jitter		—	—	±200	ps
t _{FBKDL}	External Feedback Delay		—	—	10	ns
t _{HI}	Input Clock High Time	90% to 90%	0.5	—	—	ns
t _{LO}	Input Clock Low Time	10% to 10%	0.5	—	—	ns
t _{RSTKW}	Reset Signal Pulse Width (RSTK)		10	—	—	ns
t _{RSTW}	Reset Signal Pulse Width (RST)		500	—	—	ns

1. Jitter sample is taken over 10,000 samples of the primary PLL output with clean reference clock.

2. Output clock is valid after t_{LOCK} for PLL reset and dynamic delay adjustment.

3. Using LVDS output buffers.

4. Relative to CLKOP.

Pin Information Summary (Cont.)

Pin Type		XP2-5				XP2-8				XP2-17			XP2-30			XP2-40	
		132 csBGA	144 TQFP	208 PQFP	256 ftBGA	132 csBGA	144 TQFP	208 PQFP	256 ftBGA	208 PQFP	256 ftBGA	484 fpBGA	256 ftBGA	484 fpBGA	672 fpBGA	484 fpBGA	672 fpBGA
PCI capable I/Os Bonding Out per Bank	Bank0	18	20	20	26	18	20	20	28	20	28	52	28	52	70	52	70
	Bank1	4	6	18	18	4	6	18	22	18	22	36	22	36	54	36	70
	Bank2	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0
	Bank3	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0
	Bank4	8	8	18	18	8	8	18	26	18	26	36	26	38	54	38	70
	Bank5	14	18	20	24	14	18	20	24	20	24	52	24	53	70	53	70
	Bank6	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0
	Bank7	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0

1. Minimum requirement to implement a fully functional 8-bit wide DDR bus. Available DDR interface consists of at least 12 I/Os (1 DQS + 1 DQSB + 8 DQs + 1 DM + Bank VREF1).

Logic Signal Connections

Package pinout information can be found under “Data Sheets” on the LatticeXP2 product page of the Lattice website at www.latticesemi.com/products/fpga/xp2 and in the Lattice Diamond design software.

Thermal Management

Thermal management is recommended as part of any sound FPGA design methodology. To assess the thermal characteristics of a system, Lattice specifies a maximum allowable junction temperature in all device data sheets. Designers must complete a thermal analysis of their specific design to ensure that the device and package do not exceed the junction temperature limits. Refer to the Lattice [Thermal Management](#) document to find the device/package specific thermal values.

For Further Information

- TN1139, [Power Estimation and Management for LatticeXP2 Devices](#)
- Power Calculator tool is included with the Lattice Diamond design tool or as a standalone download from www.latticesemi.com/products/designsoftware

Revision History

Date	Version	Section	Change Summary			
May 2007	01.1	—	Initial release.			
September 2007	01.2	DC and Switching Characteristics	Added JTAG Port Timing Waveforms diagram. Updated sysCLOCK PLL Timing table.			
		Pinout Information	Added Thermal Management text section.			
February 2008	01.3	Architecture	Added LVC MOS33D to Supported Output Standards table. Clarified: "This Flash can be programmed through either the JTAG or Slave SPI ports of the device. The SRAM configuration space can also be infinitely reconfigured through the JTAG and Master SPI ports." Added External Slave SPI Port to Serial TAG Memory section. Updated Serial TAG Memory diagram.			
			DC and Switching Characteristics	Updated Flash Programming Specifications table. Added "8W" specification to Hot Socketing Specifications table. Updated Timing Tables Clarifications for IIH in DC Electrical Characteristics table. Added LVC MOS33D section Updated DOA and DOA (Regs) to EBR Timing diagrams. Removed Master Clock Frequency and Duty Cycle sections from the LatticeXP2 sysCONFIG Port Timing Specifications table. These are listed on the On-chip Oscillator and Configuration Master Clock Characteristics table. Changed CSSPIN to CSSPISN in description of t_{SCS} , t_{SCSS} , and t_{SCSH} parameters. Removed t_{SOE} parameter. Clarified On-chip Oscillator documentation Added Switching Test Conditions		
				Pinout Information	Added "True LVDS Pairs Bonding Out per Bank," "DDR Banks Bonding Out per I/O Bank," and "PCI capable I/Os Bonding Out per Bank" to Pin Information Summary in place of previous blank table "PCI and DDR Capabilities of the Device-Package Combinations" Removed pinout listing. This information is available on the LatticeXP2 product web pages	
		Ordering Information			Added XP2-17 "8W" and all other family OPNs.	
		April 2008		01.4	DC and Switching Characteristics	Updated Absolute Maximum Ratings footnotes. Updated Recommended Operating Conditions Table footnotes. Updated Supply Current (Standby) Table Updated Initialization Supply Current Table Updated Programming and Erase Flash Supply Current Table Updated Register to Register Performance Table Updated LatticeXP2 External Switching Characteristics Table Updated LatticeXP2 Internal Switching Characteristics Table Updated sysCLOCK PLL Timing Table